

# SUPPORTING INFORMATION

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**Synthesis, Magnetic and NMR spectroscopic properties of  
the  $MAI_5Pt_3$  series ( $M = Ca, Y, La-Nd, Sm-Er$ )**

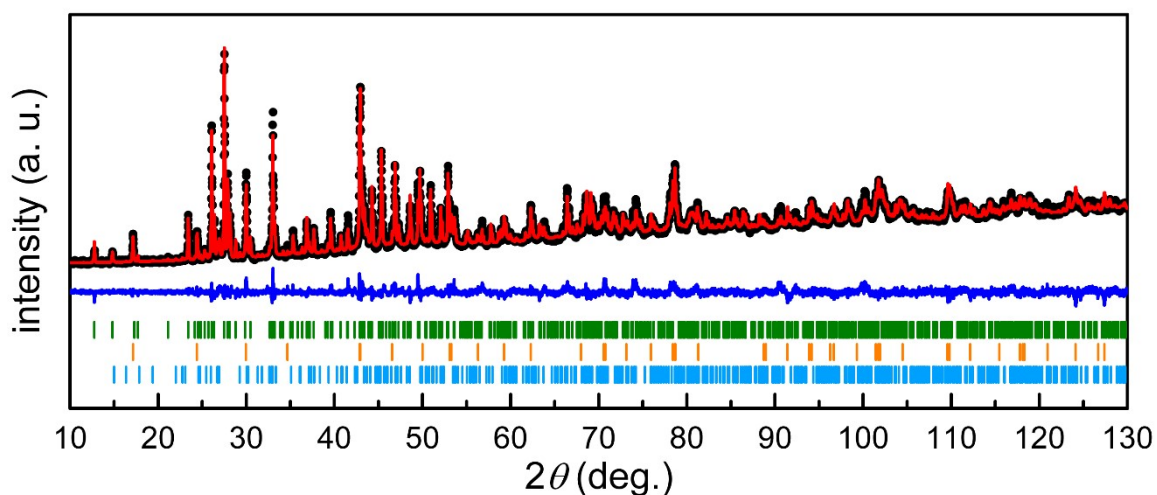
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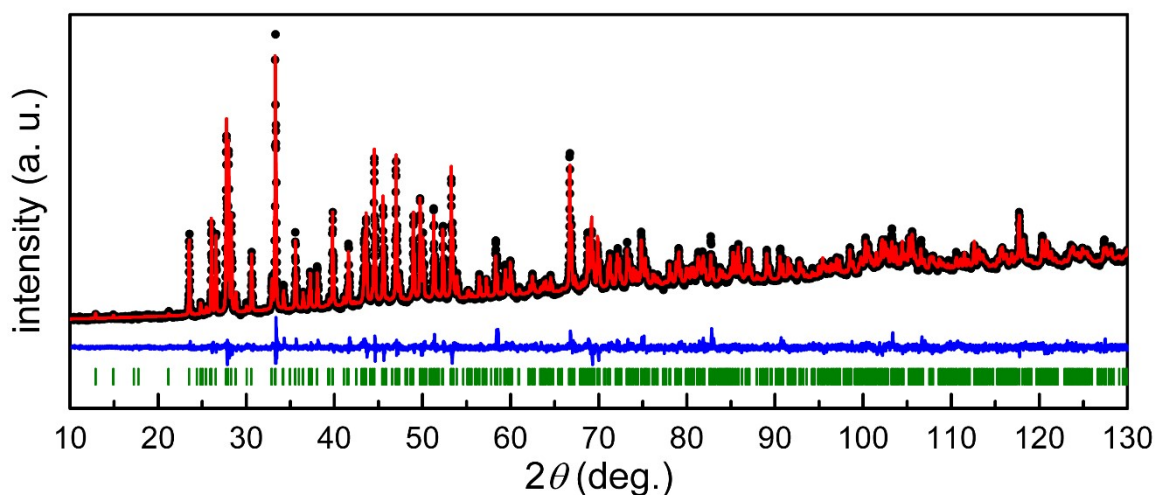
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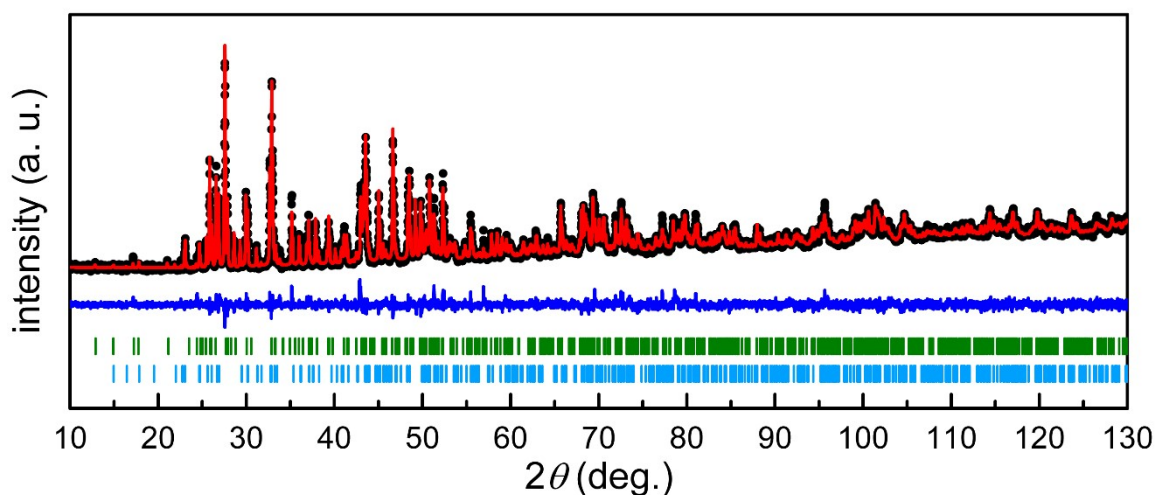
**Figure S1.** Rietveld fit of the powder X-ray diffraction pattern of  $\text{CaAl}_5\text{Pt}_3$ . Experimental data is shown as black dots, the fit as red line, the difference as blue line. The green ticks indicate the Bragg positions for  $\text{CaAl}_5\text{Pt}_3$ , the orange ticks the ones of  $\text{Al}_3\text{Pt}_2$  and the blue ones the ones of  $\text{Ca}_2\text{Al}_{16}\text{Pt}_9$ .

<b>Refinement details for the data shown in Figure S1</b>			
Source	Bruker D8 ADVANCE (laboratory X-ray)		
Temperature	RT		
Pressure	ambient		
Wavelengths	Cu $K\alpha_1$ and Cu $K\alpha_2$ : 154.0596 and 154.4308 pm		
Chemical formula	$\text{CaAl}_5\text{Pt}_3$	$\text{Al}_3\text{Pt}_2$	$\text{Ca}_2\text{Al}_{16}\text{Pt}_9$
Refined amount / wt.-%	74(1)	15(1)	11(1)
Space group	$Pnma$	$P\bar{3}m1$	$Immm$
$a$ / pm	2050.35(3)	420.75(1)	414.03(5)
$b$ / pm	409.04(1)	420.75(1)	1181.8(2)
$c$ / pm	736.37(1)	517.15(1)	1830.6(3)
$V$ / nm <sup>3</sup>	0.6176	0.0783	0.8957
$Z$	4	1	2
$d$ -space range	0.85-14.35 Å (6-130° $2\theta$ )		
$\chi^2$	2.94		
$R_p$ / %	3.62		
$R_{wp}$ / %	4.82		
Definition of $R$ factors	$R_p = \frac{\sum  w I_0 - I_c ^2 }{\sum  wI_0 ^2 }^{1/2}$		



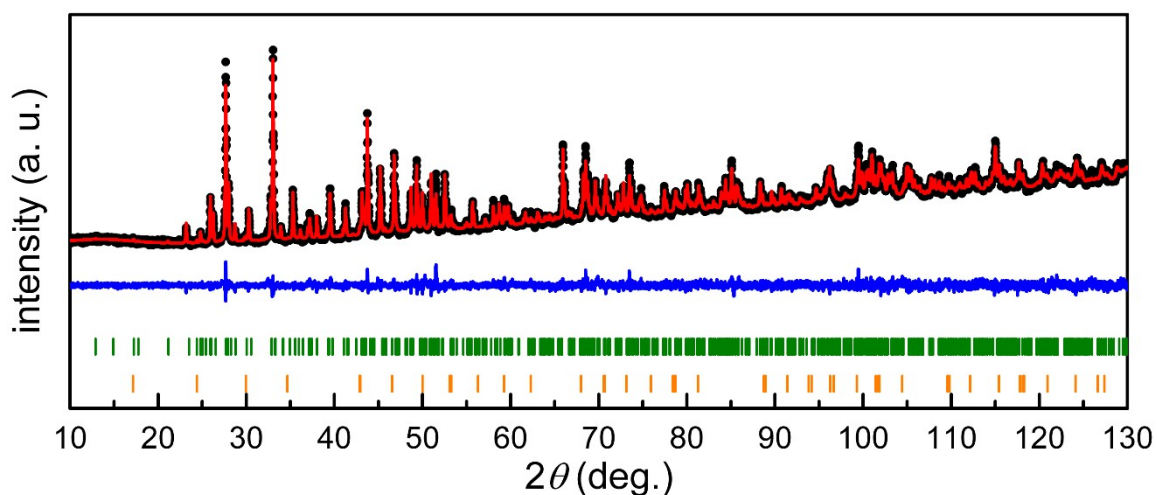
**Figure S2.** Rietveld fit of the powder X-ray diffraction pattern of  $\text{YAl}_5\text{Pt}_3$ . Experimental data is shown as black dots, the fit as red line, the difference as blue line. The green ticks indicate the Bragg positions for  $\text{YAl}_5\text{Pt}_3$ .

<b>Refinement details for the data shown in Figure S2</b>	
Source	Bruker D8 ADVANCE (laboratory X-ray)
Temperature	RT
Pressure	ambient
Wavelengths	Cu $K\alpha_1$ and Cu $K\alpha_2$ : 154.0596 and 154.4308 pm
Chemical formula	$\text{YAl}_5\text{Pt}_3$
Refined amount / wt.-%	100
Space group	$Pnma$
$a$ / pm	2052.65(2)
$b$ / pm	406.75(1)
$c$ / pm	728.77(1)
$V$ / nm <sup>3</sup>	0.6085
$Z$	4
$d$ -space range	0.85-14.35 Å (6-130° $2\theta$ )
$\chi^2$	2.83
$R_p$ / %	3.19
$R_{wp}$ / %	4.24
Definition of $R$ factors	$R_p = \frac{\sum  w   I_0 - I_c ^2}{\sum  w I_0^2 }^{1/2}$



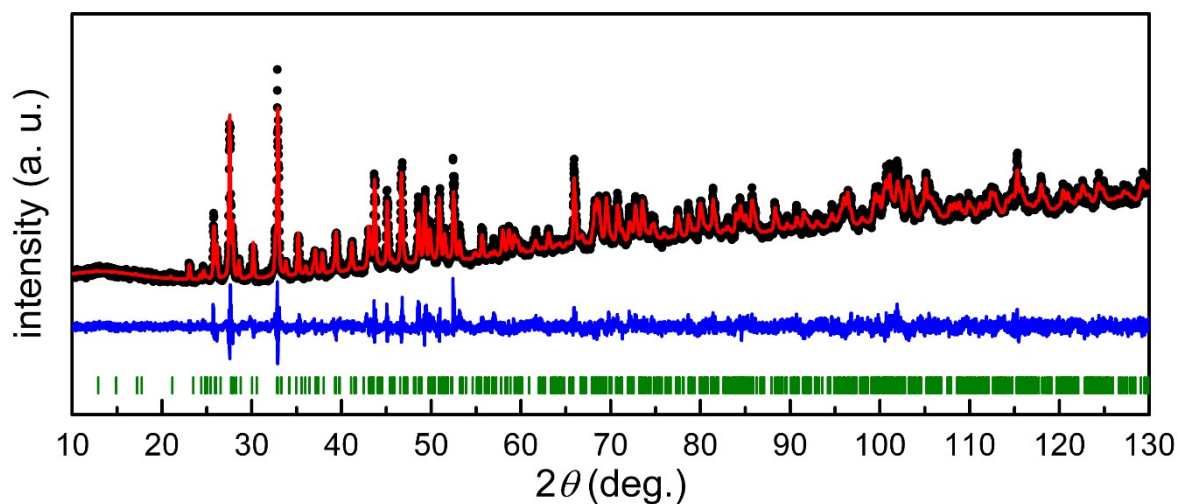
**Figure S3.** Rietveld fit of the powder X-ray diffraction pattern of  $\text{LaAl}_5\text{Pt}_3$ . Experimental data is shown as black dots, the fit as red line, the difference as blue line. The green ticks indicate the Bragg positions for  $\text{LaAl}_5\text{Pt}_3$ , the blue ones the of  $\text{La}_2\text{Al}_{16}\text{Pt}_9$ .

Refinement details for the data shown in Figure S3		
Source	Bruker D8 ADVANCE (laboratory X-ray)	
Temperature	RT	
Pressure	ambient	
Wavelengths	Cu $K\alpha_1$ and Cu $K\alpha_2$ : 154.0596 and 154.4308 pm	
Chemical formula	$\text{LaAl}_5\text{Pt}_3$	$\text{La}_2\text{Al}_{16}\text{Pt}_9$
Refined amount / wt.-%	68(1)	32(1)
Space group	$Pnma$	$Immm$
$a$ / pm	2068.53(2)	416.97(1)
$b$ / pm	415.48(1)	1187.41(3)
$c$ / pm	732.09(1)	1828.34(4)
$V$ / nm <sup>3</sup>	0.6292	0.9052
$Z$	4	2
$d$ -space range	0.85-14.35 Å (6-130° $2\theta$ )	
$\chi^2$	1.90	
$R_p$ / %	4.00	
$R_{wp}$ / %	5.28	
Definition of $R$ factors	$R_p = \frac{\sum  w   I_0 - I_c ^2}{\sum  w I_0^2 };$ $R_{wp} = \left( \frac{\sum  w   I_0 - I_c ^2}{\sum  w I_0^2 } \right)^{\frac{1}{2}}$	



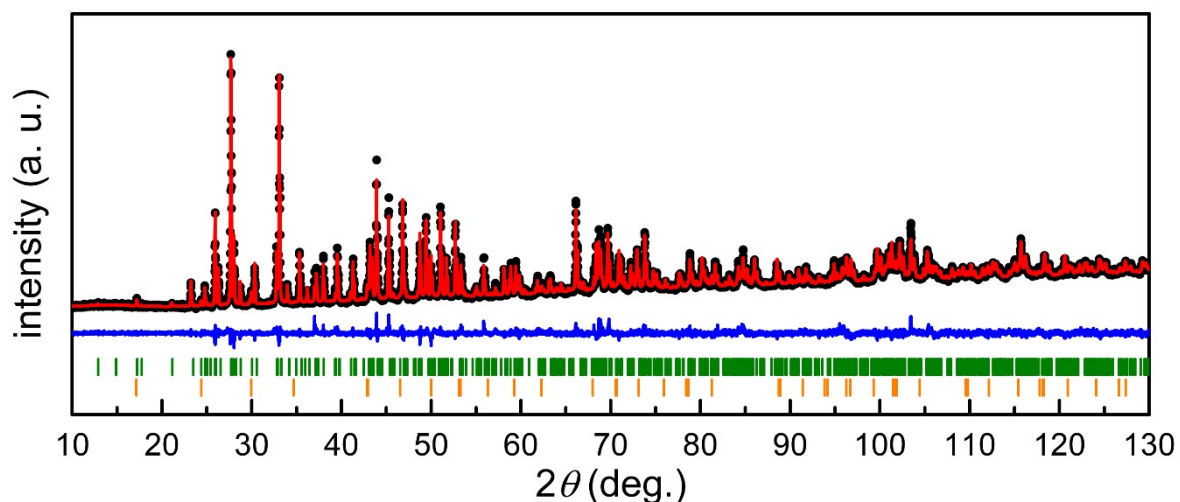
**Figure S4.** Rietveld fit of the powder X-ray diffraction pattern of  $\text{CeAl}_5\text{Pt}_3$ . Experimental data is shown as black dots, the fit as red line, the difference as blue line. The green ticks indicate the Bragg positions for  $\text{CeAl}_5\text{Pt}_3$ , the orange ticks the ones of  $\text{Al}_3\text{Pt}_2$ .

<b>Refinement details for the data shown in Figure S4</b>		
Source	Bruker D8 ADVANCE (laboratory X-ray)	
Temperature	RT	
Pressure	ambient	
Wavelengths	Cu $K\alpha_1$ and Cu $K\alpha_2$ : 154.0596 and 154.4308 pm	
Chemical formula	$\text{CeAl}_5\text{Pt}_3$	$\text{Al}_3\text{Pt}_2$
Refined amount / wt.-%	98(1)	2(1)
Space group	$Pnma$	$P\bar{3}m1$
$a$ / pm	2063.91(2)	421.43(10)
$b$ / pm	414.01(1)	421.43(10)
$c$ / pm	730.12(1)	517.4(2)
$V$ / nm <sup>3</sup>	0.6239	0.0796
$Z$	4	1
$d$ -space range	0.85-14.35 Å (6-130° $2\theta$ )	
$\chi^2$	1.58	
$R_p$ / %	3.31	
$R_{wp}$ / %	4.38	
Definition of $R$ factors	$R_p = \frac{\sum  w I_0 - I_c ^2 }{\sum  wI_0 ^2}$ $R_{wp} = \left( \frac{\sum  w I_0 - I_c ^2 }{\sum  wI_0 ^2} \right)^{\frac{1}{2}}$	



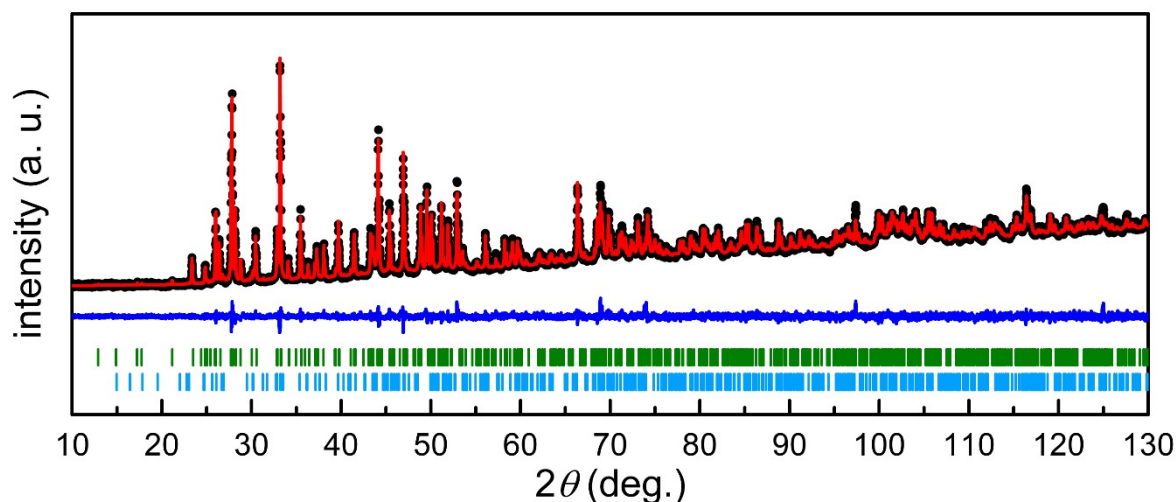
**Figure S5.** Rietveld fit of the powder X-ray diffraction pattern of  $\text{PrAl}_5\text{Pt}_3$ . Experimental data is shown as black dots, the fit as red line, the difference as blue line. The green ticks indicate the Bragg positions for  $\text{PrAl}_5\text{Pt}_3$ .

<b>Refinement details for the data shown in Figure S5</b>	
Source	Bruker D8 ADVANCE (laboratory X-ray)
Temperature	RT
Pressure	ambient
Wavelengths	$\text{Cu } K\alpha_1$ and $\text{Cu } K\alpha_2$ : 154.0596 and 154.4308 pm
Chemical formula	$\text{PrAl}_5\text{Pt}_3$
Refined amount / wt.-%	100
Space group	<i>Pnma</i>
<i>a</i> / pm	2061.43(7)
<i>b</i> / pm	412.97(1)
<i>c</i> / pm	729.64(2)
<i>V</i> / nm <sup>3</sup>	0.6212
<i>Z</i>	4
<i>d</i> -space range	0.85-14.35 Å (6-130° 2θ)
$\chi^2$	2.26
$R_p$ / %	4.14
$R_{wp}$ / %	5.53
Definition of <i>R</i> factors	$R_p = \frac{\sum  w   I_0 - I_c ^2}{\sum  w I_0^2 }^{1/2}$



**Figure S6.** Rietveld fit of the powder X-ray diffraction pattern of NdAl<sub>5</sub>Pt<sub>3</sub>. Experimental data is shown as black dots, the fit as red line, the difference as blue line. The green ticks indicate the Bragg positions for NdAl<sub>5</sub>Pt<sub>3</sub>, the orange ticks the ones of Al<sub>3</sub>Pt<sub>2</sub>.

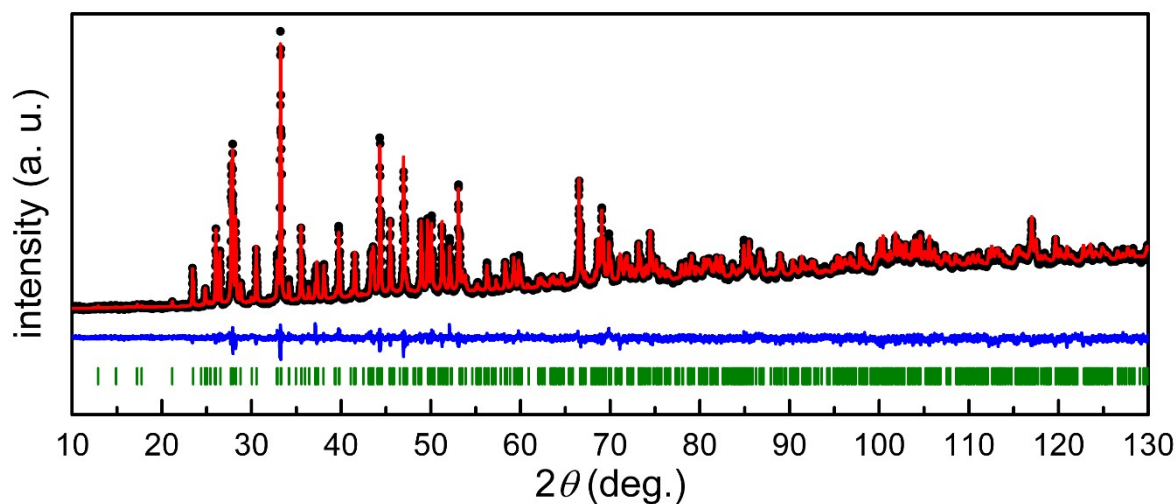
<b>Refinement details for the data shown in Figure S6</b>		
Source	Bruker D8 ADVANCE (laboratory X-ray)	
Temperature	RT	
Pressure	ambient	
Wavelengths	Cu K $\alpha_1$ and Cu K $\alpha_2$ : 154.0596 and 154.4308 pm	
Chemical formula	NdAl <sub>5</sub> Pt <sub>3</sub>	Al <sub>3</sub> Pt <sub>2</sub>
Refined amount / wt.-%	97(1)	3(1)
Space group	<i>Pnma</i>	$\bar{P}3m1$
<i>a</i> / pm	2059.92(1)	421.56(3)
<i>b</i> / pm	412.05(1)	421.56(3)
<i>c</i> / pm	729.26(1)	515.12(7)
<i>V</i> / nm <sup>3</sup>	0.6190	0.0793
<i>Z</i>	4	1
<i>d</i> -space range	0.85-14.35 Å (6-130° 2 $\theta$ )	
$\chi^2$	2.22	
<i>R<sub>p</sub></i> / %	3.49	
<i>R<sub>wp</sub></i> / %	4.65	
Definition of <i>R</i> factors	$R_p = \frac{\sum  w I_0 - I_c ^2 }{\sum  wI_0^2 }$	



**Figure S7.** Rietveld fit of the powder X-ray diffraction pattern of  $\text{SmAl}_5\text{Pt}_3$ . Experimental data is shown as black dots, the fit as red line, the difference as blue line. The green ticks indicate the Bragg positions for  $\text{SmAl}_5\text{Pt}_3$ , the blue ones the of  $\text{Sm}_2\text{Al}_{16}\text{Pt}_9$ .

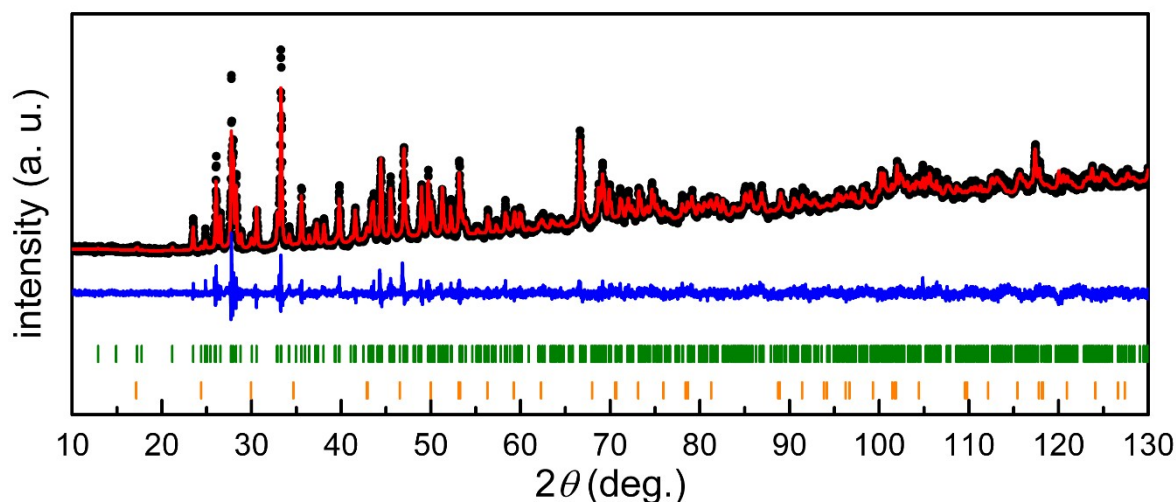
Refinement details for the data shown in Figure S7		
Source	Bruker D8 ADVANCE (laboratory X-ray)	
Temperature	RT	
Pressure	ambient	
Wavelengths	Cu $K\alpha_1$ and Cu $K\alpha_2$ : 154.0596 and 154.4308 pm	
Chemical formula	$\text{SmAl}_5\text{Pt}_3$	$\text{Sm}_2\text{Al}_{16}\text{Pt}_9$
Refined amount / wt.-%	95(1)	5(1)
Space group	<i>Pnma</i>	<i>Immm</i>
<i>a</i> / pm	2057.02(2)	413.95(7)
<i>b</i> / pm	410.24(1)	1184.8(2)
<i>c</i> / pm	728.52(1)	1816.4(4)
<i>V</i> / nm <sup>3</sup>	0.6148	0.8909
<i>Z</i>	4	2
<i>d</i> -space range	0.85-14.35 Å (6-130° 2θ)	
$\chi^2$	1.69	
$R_p$ / %	2.89	
$R_{wp}$ / %	3.82	
Definition of <i>R</i> factors	$R_p = \frac{\sum  w I_0 - I_c ^2 }{\sum  wI_0 ^2}^{1/2}$	





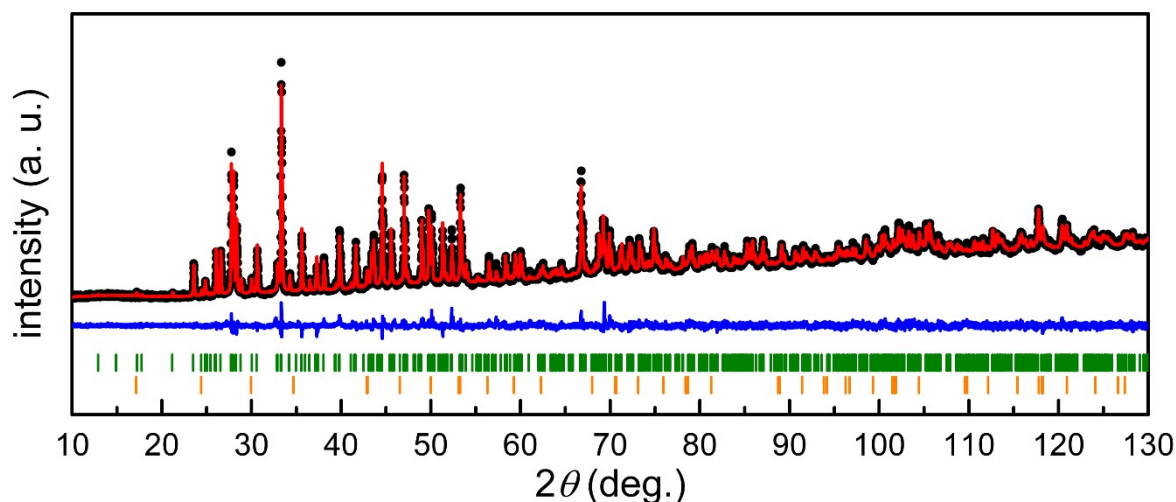
**Figure S8.** Rietveld fit of the powder X-ray diffraction pattern of  $\text{GdAl}_5\text{Pt}_3$ . Experimental data is shown as black dots, the fit as red line, the difference as blue line. The green ticks indicate the Bragg positions for  $\text{GdAl}_5\text{Pt}_3$ .

<b>Refinement details for the data shown in Figure S8</b>	
Source	Bruker D8 ADVANCE (laboratory X-ray)
Temperature	RT
Pressure	ambient
Wavelengths	$\text{Cu } K\alpha_1$ and $\text{Cu } K\alpha_2$ : 154.0596 and 154.4308 pm
Chemical formula	$\text{GdAl}_5\text{Pt}_3$
Refined amount / wt.-%	100
Space group	<i>Pnma</i>
<i>a</i> / pm	2054.93(2)
<i>b</i> / pm	408.65(1)
<i>c</i> / pm	728.29(1)
<i>V</i> / nm <sup>3</sup>	0.6116
<i>Z</i>	4
<i>d</i> -space range	0.85-14.35 Å (6-130° 2θ)
$\chi^2$	1.75
$R_p$ / %	2.95
$R_{wp}$ / %	3.85
Definition of <i>R</i> factors	$R_p = \frac{\sum  w I_0 - I_c ^2 }{\sum  wI_0 ^2}$ $R_{wp} = \left( \frac{\sum  w I_0 - I_c ^2 }{\sum  wI_0 ^2} \right)^{\frac{1}{2}}$



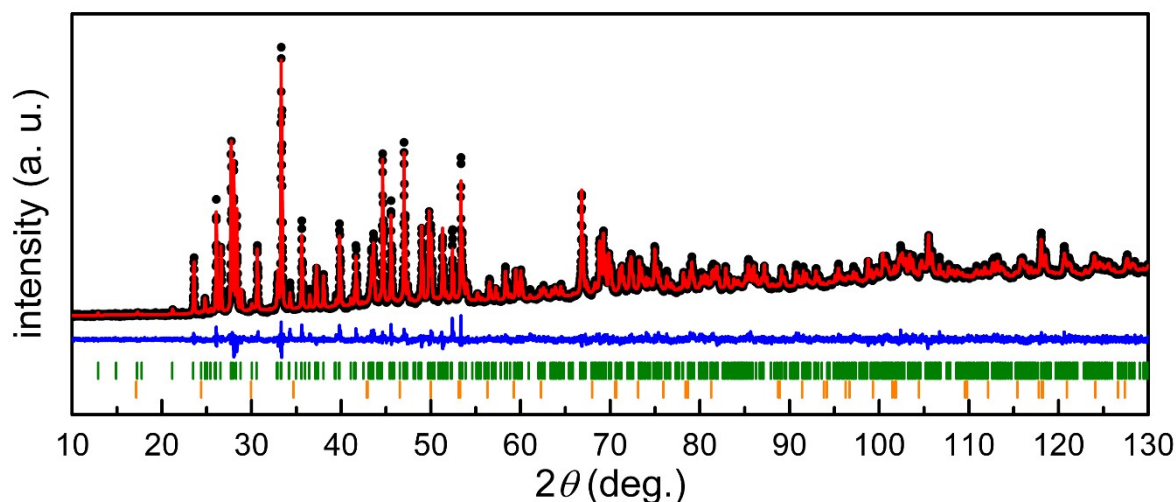
**Figure S9.** Rietveld fit of the powder X-ray diffraction pattern of  $\text{TbAl}_5\text{Pt}_3$ . Experimental data is shown as black dots, the fit as red line, the difference as blue line. The green ticks indicate the Bragg positions for  $\text{TbAl}_5\text{Pt}_3$ , the orange ticks the ones of  $\text{Al}_3\text{Pt}_2$ .

<b>Refinement details for the data shown in Figure S9</b>		
Source	Bruker D8 ADVANCE (laboratory X-ray)	
Temperature	RT	
Pressure	ambient	
Wavelengths	Cu $K\alpha_1$ and Cu $K\alpha_2$ : 154.0596 and 154.4308 pm	
Chemical formula	$\text{TbAl}_5\text{Pt}_3$	$\text{Al}_3\text{Pt}_2$
Refined amount / wt.-%	96(1)	4(1)
Space group	$Pnma$	$\bar{P}3m1$
$a$ / pm	2053.22(4)	421.3(2)
$b$ / pm	407.67(1)	421.3(2)
$c$ / pm	728.28(2)	517.0(5)
$V$ / nm <sup>3</sup>	0.6096	0.0795(1)
$Z$	4	1
$d$ -space range	0.85-14.35 Å (6-130° $2\theta$ )	
$\chi^2$	2.69	
$R_p$ / %	3.93	
$R_{wp}$ / %	5.48	
Definition of $R$ factors	$R_p = \frac{\sum  w   I_0 - I_c ^2}{\sum  w I_0^2 }$ $R_{wp} = \left( \frac{\sum  w   I_0 - I_c ^2}{\sum  w I_0^2 } \right)^{\frac{1}{2}}$	



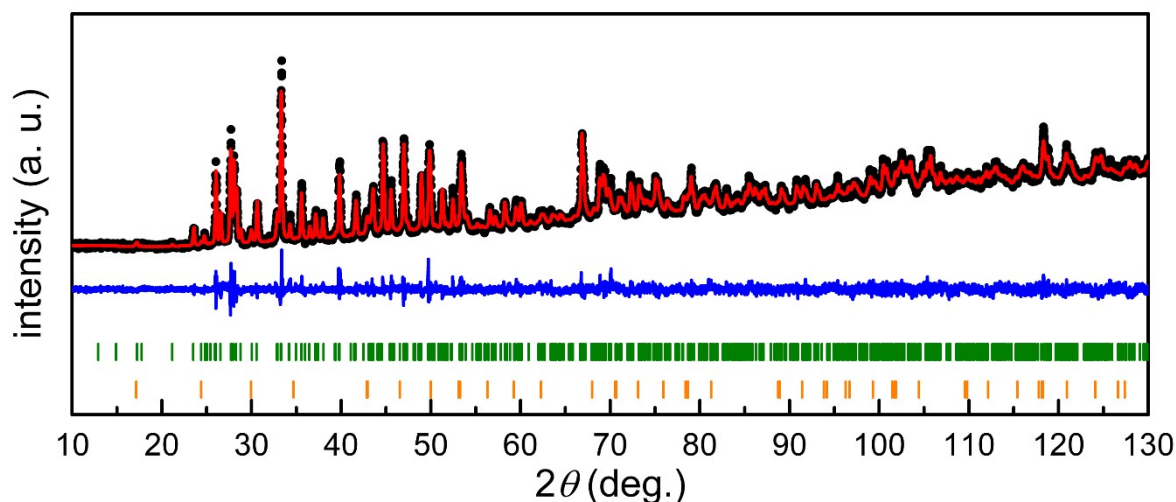
**Figure S10.** Rietveld fit of the powder X-ray diffraction pattern of  $\text{DyAl}_5\text{Pt}_3$ . Experimental data is shown as black dots, the fit as red line, the difference as blue line. The green ticks indicate the Bragg positions for  $\text{DyAl}_5\text{Pt}_3$ , the orange ticks the ones of  $\text{Al}_3\text{Pt}_2$ .

<b>Refinement details for the data shown in Figure S10</b>		
Source	Bruker D8 ADVANCE (laboratory X-ray)	
Temperature	RT	
Pressure	ambient	
Wavelengths	Cu $K\alpha_1$ and Cu $K\alpha_2$ : 154.0596 and 154.4308 pm	
Chemical formula	$\text{DyAl}_5\text{Pt}_3$	$\text{Al}_3\text{Pt}_2$
Refined amount / wt.-%	97(1)	3(1)
Space group	$Pnma$	$\bar{P}3m1$
$a$ / pm	2051.95(2)	421.12(3)
$b$ / pm	406.67(1)	421.12(3)
$c$ / pm	728.59(1)	516.96(7)
$V$ / nm <sup>3</sup>	0.6079	0.0794
$Z$	4	1
$d$ -space range	0.85-14.35 Å (6-130° $2\theta$ )	
$\chi^2$	1.92	
$R_p$ / %	3.01	
$R_{wp}$ / %	4.02	
Definition of $R$ factors	$R_p = \frac{\sum  w   I_0 - I_c ^2}{\sum  w I_0^2 }$	



**Figure S11.** Rietveld fit of the powder X-ray diffraction pattern of  $\text{HoAl}_5\text{Pt}_3$ . Experimental data is shown as black dots, the fit as red line, the difference as blue line. The green ticks indicate the Bragg positions for  $\text{HoAl}_5\text{Pt}_3$ , the orange ticks the ones of  $\text{Al}_3\text{Pt}_2$ .

<b>Refinement details for the data shown in Figure S11</b>		
Source	Bruker D8 ADVANCE (laboratory X-ray)	
Temperature	RT	
Pressure	ambient	
Wavelengths	Cu $K\alpha_1$ and Cu $K\alpha_2$ : 154.0596 and 154.4308 pm	
Chemical formula	$\text{HoAl}_5\text{Pt}_3$	$\text{Al}_3\text{Pt}_2$
Refined amount / wt.-%	99(1)	1(1)
Space group	$Pnma$	$\bar{P}3m1$
$a$ / pm	2050.36(2)	420.6(5)
$b$ / pm	405.89(1)	420.6(5)
$c$ / pm	729.07(1)	510.0(12)
$V$ / nm <sup>3</sup>	0.6067	0.0781
$Z$	4	1
$d$ -space range	0.85-14.35 Å (6-130° $2\theta$ )	
$\chi^2$	2.15	
$R_p$ / %	3.08	
$R_{wp}$ / %	4.09	
Definition of $R$ factors	$R_p = \frac{\sum  w   I_0 - I_c ^2}{\sum  w I_0^2 }$	



**Figure S12.** Rietveld fit of the powder X-ray diffraction pattern of  $\text{ErAl}_5\text{Pt}_3$ . Experimental data is shown as black dots, the fit as red line, the difference as blue line. The green ticks indicate the Bragg positions for  $\text{ErAl}_5\text{Pt}_3$ , the orange ticks the ones of  $\text{Al}_3\text{Pt}_2$ .

Refinement details for the data shown in Figure S12		
Source	Bruker D8 ADVANCE (laboratory X-ray)	
Temperature	RT	
Pressure	ambient	
Wavelengths	Cu $K\alpha_1$ and Cu $K\alpha_2$ : 154.0596 and 154.4308 pm	
Chemical formula	$\text{ErAl}_5\text{Pt}_3$	$\text{Al}_3\text{Pt}_2$
Refined amount / wt.-%	96(1)	4(1)
Space group	$Pnma$	$P\bar{3}m1$
$a$ / pm	2049.24(5)	420.86(7)
$b$ / pm	405.11(1)	420.86(7)
$c$ / pm	729.74(2)	517.0(2)
$V$ / nm <sup>3</sup>	0.6058	0.0791
$Z$	4	1
$d$ -space range	0.85-14.35 Å (6-130° $2\theta$ )	
$\chi^2$	2.11	
$R_p$ / %	3.57	
$R_{wp}$ / %	4.78	
Definition of $R$ factors	$R_p = \frac{\sum  w   I_0 - I_c ^2}{\sum  w I_0^2 };$ $R_{wp} = \left( \frac{\sum  w   I_0 - I_c ^2}{\sum  w I_0^2 } \right)^{\frac{1}{2}}$	